

## 1. General Requirements

All components have to be mounted according to the drawing: GAA26800MX  
The bare board is specified as: GAA610ADB

## 2. Revision History

Version	Date	Revised by	Description
1.0	2010-APR-13	A. Tutat	Initial Version
1.1	2010-MAY-28	A. Tutat	some limits adapted
1.2	2010-DEC-28	A. Tutat	test cases PTC not required
1.3	2011-JAN-06	A. Tutat	SMPS load resistors (2k)

## 3. Code Requirements

The board has been laid out according to the requirements in EN81, VDE110-1 (Transient Voltage 4kV; Inhomogeneous Field, Pollution Degree 2 and Safety relevant areas to other areas: Pollution Degree 3; Clearance Distance: Table2; Creepage Distance: Table

Date	Changes	Name	Test Requirement for PBX_BIDI	GAA26800MX_TR		
2010-MAY-28	some limits adapted, CA47A-000528	A. Tutat		12 SHEETS - SHEET 1		
2010-DEC-28	test cases PTC not required, CA47A-000528	A. Tutat	OTIS Elevator Company Enigneering Center Berlin	RESP	2010-APR-13	A. Tutat
2011-JAN-06	SMPS load resistors (2k), CA47A-000528	A. Tutat		CHK	2010-APR-13	M. Dehmlow
				AUT	2010-APR-13	CA47A-000528

#### 4. Data logging Requirements for the purpose of statistical analysis.

All measurement results should be written together with the PCB serial number and production-date into a file.  
The time-interval to produce a back-up of the file should be determined by the factory. Also must be determined how many records are captured per file.

Construction of the file:

1. PCB serial number
  2. production-date
  3. all measurement results, The variable-names should consist of a combination of Symbol-Name and Parameter-Name.)
- Visual separation through special character, for example: \*\*\*\*\*.

#### 5. Electrical Requirements

Unless otherwise noted MIN/MAX values are valid for temperatures between +0degC and +70degC.  
All typical values are calculated for an ambient temperature of Ta=25degC.

DC values have to be measured with an average reading meter. AC values have to be measured with a true-RMS meter.  
DC values are marked with the unit V or A, AC values are marked with Vrms or Arms.

The remark "Logic Level" (LL) relates to HCMOS standard: "High" = 3.5V ... 5.7V and "Low"=-0.7V ... 1.0V.

Date	Changes	Name	Test Requirement for PBX_BIDI	GAA26800MX_TR		
2010-MAY-28	some limits adapted, CA47A-000528	A. Tutat		12 SHEETS - SHEET 2		
2010-DEC-28	test cases PTC not required, CA47A-000528	A. Tutat	OTIS Elevator Company Enigneering Center Berlin	RESP	2010-APR-13	A. Tutat
2011-JAN-06	SMPS load resistors (2k), CA47A-000528	A. Tutat		CHK	2010-APR-13	M. Dehmlow
				AUT	2010-APR-13	CA47A-000528

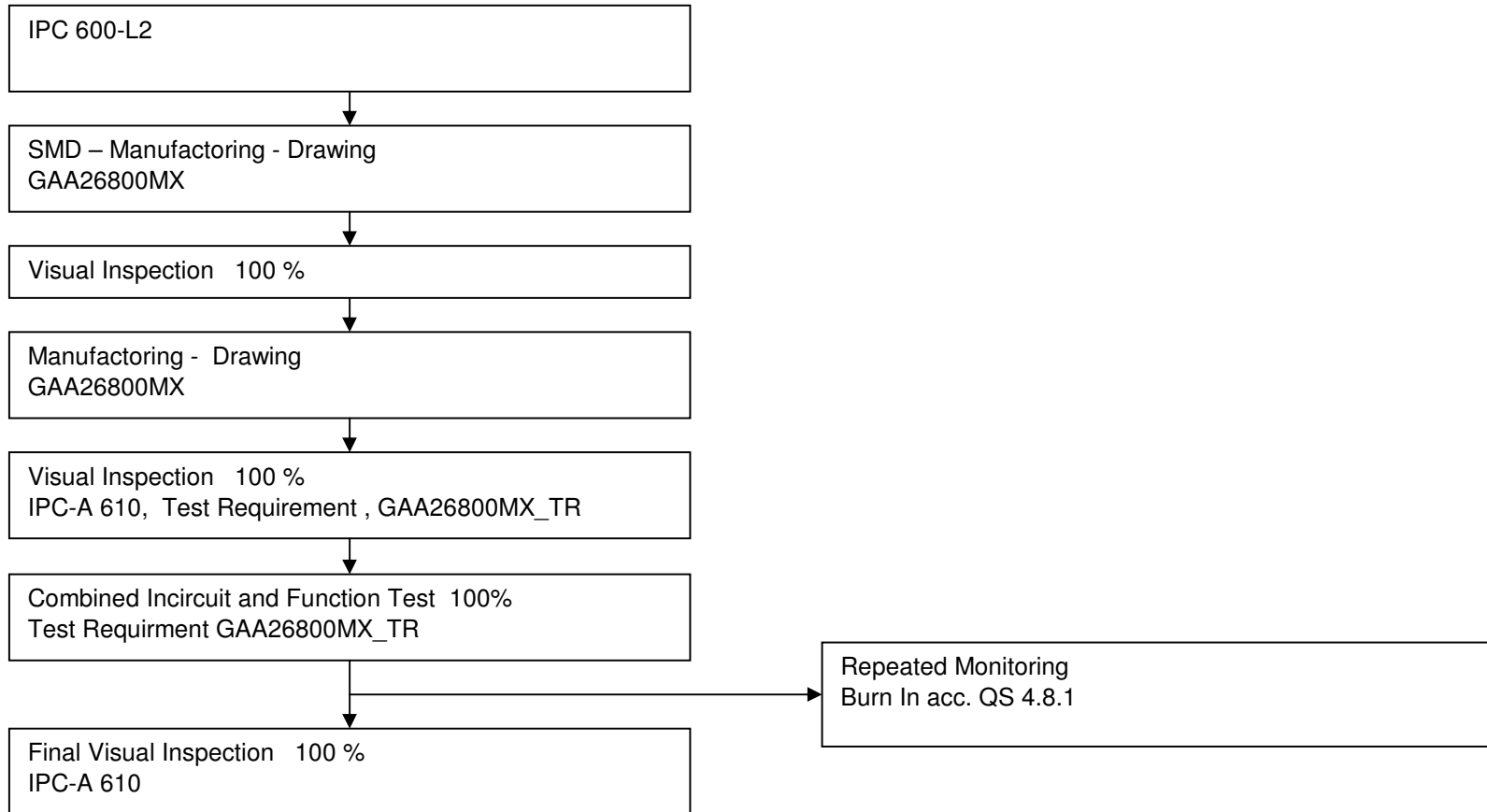
## 5.1. Power supply

If within the test cases no other supply voltages are indicated,  
the board has to be supplied with the following voltages:

24V_HL2 HL2	+24V / current limitable to max. 500mA at P5.46 (referenced to HL2) at P5.44
24V_SE 24V_SE_RTN	+24V / current limitable to max. 500mA at P1.1 (referenced to 24V_SE_RTN) at P1.2
24V_SW 24V_SW_RTN	+24V / current limitable to max. 500mA at P4.1 (referenced to 24V_SW_RTN) at P4.2
24V_SENSE 24V_SENSE_RTN	+24V / current limitable to max. 500mA at P5.50 (referenced to 24V_SENSE_RTN) at P5.48
V+15V V-15V AGND	+15V / current limitable to max. 200mA at P3.40 (referenced to AGND) -15V / current limitable to max. 200mA at P3.39 (referenced to AGND) at P3.38
VCC GND	+5V / current limitable to max. 200mA at P3.13 (referenced to GND) at P3.12

Date	Changes	Name	Test Requirement for PBX_BIDI	GAA26800MX_TR		
2010-MAY-28	some limits adapted, CA47A-000528	A. Tutat		12 SHEETS - SHEET 3		
2010-DEC-28	test cases PTC not required, CA47A-000528	A. Tutat	OTIS Elevator Company Engineering Center Berlin	RESP	2010-APR-13	A. Tutat
2011-JAN-06	SMPS load resistors (2k), CA47A-000528	A. Tutat		CHK	2010-APR-13	M. Dehmlow
				AUT	2010-APR-13	CA47A-000528

## 6. Test Flow



Date	Changes	Name	Test Requirement for PBX_BIDI	GAA26800MX_TR		
2010-MAY-28	some limits adapted, CA47A-000528	A. Tutat		12 SHEETS - SHEET 4		
2010-DEC-28	test cases PTC not required, CA47A-000528	A. Tutat	OTIS Elevator Company Enigneering Center Berlin	RESP	2010-APR-13	A. Tutat
2011-JAN-06	SMPS load resistors (2k), CA47A-000528	A. Tutat		CHK	2010-APR-13	M. Dehmlow
				AUT	2010-APR-13	CA47A-000528

Test Requirement for PBX_BIDI GAA26800MX					Samples										Value range  Lower Specification Limit Upper Specification Limit			
1. All measuring instruments must be calibrated!!! 2. As an additional document, the circuit diagram of the PCBA is required. 3. All measuring points : reference points are described in kind of netnames, test points or component designator. 4. PBX_BIDI alternatively assembled with CONVERTER- or INVERTER-FUNCTIONALITY test cases <b>only</b> for PBX_BIDI, <b>INVERTER</b> -FUNCTIONALITY, GAA26800MX1, marked with note: 1 test cases <b>only</b> for PBX_BIDI, <b>CONVERTER</b> -FUNCTIONALITY, GAA26800MX2, marked with note: 2 test cases <b>not required for GAA26800MX1, GAA26800MX2</b> , marked with note: 4 5. Highly Accelerated Life Test, test cases required for <b>HALT</b> , marked with note: 3																		
Test cases					Board Serial Number										LSL	Typical	USL	
Description	note	note	measuring point : reference point @ specified condition	unit														
Power Supply: IGBT Gate Driver PHASE R(U)	1		quiescent current consumption: 24V_SW @ 24VDC <b>current: IGBT driver SMPS</b>	mA										180,00	236,00	290,00		
SMPS characteristic Switched Mode Power Supply	2		quiescent current consumption: 24V_SE @ 24VDC <b>current: IGBT driver SMPS, SENSING SMPS</b>												180,00	236,00	360,00	
Power Fail Detection			PWM VCC_RU : 24V_DRIVER_RTN	V										10,00	11,00	13,00		
		I_SENSE_RU : 24V_DRIVER_RTN										0,10	0,60	0,90				
preparation: Please add additional load resistors (2k) to: 1.) +27V_RU_P : +27V_RU_P_RTN 2.) +27V_RU_N : +27V_RU_N_RTN			SWITCHING ON-DUTY-CYCLE w/o any additional load PWM CONTROLLER output pin or MOSFET DRAIN GATE_SENSE_RU : 24_DRIVER_RTN DRAIN_RU : 24_DRIVER_RTN	%										5,00	20,00	30,00		
			SWITCHING FREQUENCY PWM CONTROLLER output pin or MOSFET DRAIN GATE_SENSE_RU : 24_DRIVER_RTN DRAIN_RU : 24_DRIVER_RTN	kHz											140,00	160,00	180,00	
	3		+27V_RU_P : +27V_RU_P_RTN	V											26,00	27,00	29,00	
	3		+27V_RU_N : +27V_RU_N_RTN												26,00	27,00	29,00	
			REF_3V9_RU_P : +27V_RU_P_RTN													6,50	7,00	7,50
			REF_2V5_RU_P : +27V_RU_P_RTN													2,38	2,50	2,63
			PF_IGBT threshold voltage Increase +27V_RU_P from 0V until output a transition occurs: HIGH to LOW MX1: PF_IGBT_INV : GND MX2: PF_IGBT_CONV : GND  preparation: disconnect primary 24V_SW and 24V_SE supply, add an adjustable supply only on +27V_RU_P referenced to +27V_RU_P_RTN													2,00	2,40	3,10
			REF_3V9_RU_N : +27V_RU_N_RTN													6,50	7,00	7,50
			REF_2V5_RU_N : +27V_RU_N_RTN													2,38	2,50	2,63
			PF_IGBT threshold voltage Increase +27V_RU_N from 0V until output a transition occurs: HIGH to LOW MX1: PF_IGBT_INV : GND MX2: PF_IGBT_CONV : GND  preparation: disconnect primary 24V_SW and 24V_SE supply, add an adjustable supply only on +27V_RU_N referenced to +27V_RU_N_RTN														2,00	2,40

Test Requirement for PBX\_BIDI GAA26800MX

1. All measuring instruments must be calibrated!!!  
2. As an additional document, the circuit diagram of the PCBA is required.  
3. All measuring points : reference points are described in kind of netnames, test points or component designator.  
4. PBX\_BIDI alternatively assembled with CONVERTER- or INVERTER-FUNCTIONALITY  
test cases **only** for PBX\_BIDI, **INVERTER**-FUNCTIONALITY, GAA26800**MX1**, marked with note: 1  
test cases **only** for PBX\_BIDI, **CONVERTER**-FUNCTIONALITY, GAA26800**MX2**, marked with note: 2  
test cases **not required for GAA26800MX1, GAA26800MX2**, marked with note: 4  
5. Highly Accelerated Life Test, test cases required for **HALT**, marked with note: 3

					Samples												Value range		
																	Lower Specification Limit Upper Specification Limit		
Test cases					Board Serial Number												LSL	Typical	USL
Description	note	note	measuring point : reference point @ specified condition	unit															
Power Supply: IGBT Gate Driver PHASE S(V)  SMPS characteristic Switched Mode Power Supply  Power Fail Detection  preparation: Please add additional load resistors (2k) to: 1.) +27V_SV_P : +27V_SV_P_RTN 2.) +27V_SV_N : +27V_SV_N_RTN			PWM_VCC_SV : 24V_DRIVER_RTN	V													10,00	11,00	13,00
			I_SENSE_SV : 24V_DRIVER_RTN														0,10	0,60	0,90
			SWITCHING ON-DUTY-CYCLE w/o any additional load														5,00	20,00	30,00
			PWM CONTROLLER output pin or MOSFET DRAIN																
			GATE_SENSE_SV : 24_DRIVER_RTN	%															
			DRAIN_SV : 24_DRIVER_RTN																
			SWITCHING FREQUENCY														140,00	160,00	180,00
			PWM CONTROLLER output pin or MOSFET DRAIN																
			GATE_SENSE_RU : 24_DRIVER_RTN	kHz															
			DRAIN_RU : 24_DRIVER_RTN																
	3		+27V_SV_P : +27V_SV_P_RTN	V													26,00	27,00	29,00
	3		+27V_SV_N : +27V_SV_N_RTN														26,00	27,00	29,00
			REF_3V9_SV_P : +27V_SV_P_RTN														6,50	7,00	7,50
			REF_2V5_SV_P : +27V_SV_P_RTN														2,38	2,50	2,63
			PF_IGBT threshold voltage Increase +27V_SV_P from 0V until output a transition occurs: HIGH to LOW MX1: PF_IGBT_INV : GND MX2: PF_IGBT_CONV : GND  preparation: disconnect primary 24V_SW and 24V_SE supply, add an adjustable supply only on +27V_SV_P referenced to +27V_SV_P_RTN														2,00	2,40	3,10
			REF_3V9_SV_N : +27V_SV_N_RTN														6,50	7,00	7,50
			REF_2V5_SV_N : +27V_SV_N_RTN														2,38	2,50	2,63
			PF_IGBT threshold voltage Increase +27V_SV_N from 0V until output a transition occurs: HIGH to LOW MX1: PF_IGBT_INV : GND MX2: PF_IGBT_CONV : GND  preparation: disconnect primary 24V_SW and 24V_SE supply, add an adjustable supply only on +27V_SV_N referenced to +27V_SV_N_RTN														2,00	2,40	3,10

Test Requirement for PBX_BIDI GAA26800MX																											
1. All measuring instruments must be calibrated!!! 2. As an additional document, the circuit diagram of the PCBA is required. 3. All measuring points : reference points are described in kind of netnames, test points or component designator. 4. PBX_BIDI alternatively assembled with CONVERTER- or INVERTER-FUNCTIONALITY test cases <b>only</b> for PBX_BIDI, <b>INVERTER</b> -FUNCTIONALITY, GAA26800MX1, marked with note: 1 test cases <b>only</b> for PBX_BIDI, <b>CONVERTER</b> -FUNCTIONALITY, GAA26800MX2, marked with note: 2 test cases <b>not required for GAA26800MX1, GAA26800MX2</b> , marked with note: 4 5. Highly Accelerated Life Test, test cases required for <b>HALT</b> , marked with note: 3															Samples										Value range  Lower Specification Limit Upper Specification Limit		
Test cases																											
Description		note	note	measuring point : reference point @ specified condition		unit											LSL	Typical	USL								
Power Supply: IGBT Gate Driver PHASE T(W)				PWM_VCC_TW : 24V_DRIVER_RTN		V											10,00	11,00	13,00								
				I_SENSE_TW : 24V_DRIVER_RTN													0,10	0,60	0,90								
SMPS characteristic				SWITCHING ON-DUTY-CYCLE w/o any additional load													5,00	20,00	30,00								
Switched Mode Power Supply				PWM CONTROLLER output pin or MOSFET DRAIN		%																					
				GATE_SENSE_TW : 24_DRIVER_RTN																							
Power Fail Detection				DRAIN_TW : 24_DRIVER_RTN																							
				SWITCHING FREQUENCY													140,00	160,00	180,00								
preparation:				PWM CONTROLLER output pin or MOSFET DRAIN		kHz																					
Please add additional load resistors (2k) to:				GATE_SENSE_TW : 24_DRIVER_RTN																							
				DRAIN_TW : 24_DRIVER_RTN																							
1.)		3		+27V_TW_P : +27V_TW_P_RTN		V											26,00	27,00	29,00								
+27V_TW_P : +27V_TW_P_RTN		3		+27V_TW_N : +27V_TW_N_RTN													26,00	27,00	29,00								
2.)				REF_3V9_TW_P : +27V_TW_P_RTN													6,50	7,00	7,50								
+27V_TW_N : +27V_TW_N_RTN				REF_2V5_TW_P : +27V_TW_P_RTN													2,38	2,50	2,63								
				PF_IGBT threshold voltage													2,00	2,40	3,10								
				Increase +27V_TW_P from 0V until output a transition occurs: HIGH to LOW																							
				MX1: PF_IGBT_INV : GND																							
				MX2: PF_IGBT_CONV : GND																							
				preparation:																							
				disconnect primary 24V_SW and 24V_SE supply,																							
				add an adjustable supply only on																							
				+27V_TW_P referenced to +27V_TW_P_RTN																							
				REF_3V9_TW_N : +27V_TW_N_RTN													6,50	7,00	7,50								
				REF_2V5_TW_N : +27V_TW_N_RTN													2,38	2,50	2,63								
				PF_IGBT threshold voltage													2,00	2,40	3,10								
				Increase +27V_TW_N from 0V until output a transition occurs: HIGH to LOW																							
				MX1: PF_IGBT_INV : GND																							
				MX2: PF_IGBT_CONV : GND																							
				preparation:																							
				disconnect primary 24V_SW and 24V_SE supply,																							
				add an adjustable supply only on																							
				+27V_RU_N referenced to +27V_RU_N_RTN																							



Test Requirement for PBX_BIDI GAA26800MX																				
1. All measuring instruments must be calibrated!!! 2. As an additional document, the circuit diagram of the PCBA is required. 3. All measuring points : reference points are described in kind of netnames, test points or component designator. 4. PBX_BIDI alternatively assembled with CONVERTER- or INVERTER-FUNCTIONALITY test cases <b>only</b> for PBX_BIDI, <b>INVERTER</b> -FUNCTIONALITY,   GAA26800MX1, marked with note: 1 test cases <b>only</b> for PBX_BIDI, <b>CONVERTER</b> -FUNCTIONALITY, GAA26800MX2, marked with note: 2 test cases <b>not required for GAA26800MX1, GAA26800MX2</b> marked with note: 4 5. Highly Accelerated Life Test, test cases required for <b>HALT</b> , marked with note: 3										Samples								Value range  Lower Specification Limit Upper Specification Limit		
Test cases					Board Serial Number								LSL	Typical	USL					
Description	note	note	measuring point : reference point @ specified condition	unit																
Power Supply: SENSING  SMPS characteristic Switched Mode Power Supply	1		quiescent current consumption: 24V_SENSE @ 24VDC current: SENSING SMPS	mA											20,00	100,00	200,00			
			VCC_PWM_CONTROLLER : 24V_SMPS_SENSE_RTN	V											10,00	12,00	14,00			
			I_SENSE_PWM_CONTROLLER : 24V_SMPS_SENSE_RTN												0,10	0,60	0,90			
	1		SWITCHING ON-DUTY-CYCLE PWM CONTROLLER output pin or MOSFET DRAIN SMPS_SENSE_GATE : 24V_SMPS_SENSE_RTN SMPS_SENSE_DRAIN : 24V_SMPS_SENSE_RTN	%											22,00	27,00	32,00			
	2		SWITCHING ON-DUTY-CYCLE PWM CONTROLLER output pin or MOSFET DRAIN SMPS_SENSE_GATE : 24V_SMPS_SENSE_RTN SMPS_SENSE_DRAIN : 24V_SMPS_SENSE_RTN	%											22,00	39,00	44,00			
			SWITCHING FREQUENCY PWM CONTROLLER output pin or MOSFET DRAIN SMPS_SENSE_GATE : 24V_SMPS_SENSE_RTN SMPS_SENSE_DRAIN : 24V_SMPS_SENSE_RTN	kHz											140,00	160,00	180,00			
	3		InvTempUref (Addr.: 0x10) CnvTempUref (Addr.: 0x10) measuring point: S+15V / SGND signal: +15V_SENSE / GND_SENSE	mV											14250,00	15000,00	15750,00			
	3		-15V_SENSE : GND_SENSE												-15750,00	-15000,00	-14250,00			
Power Supply: PTC Temperature Measurement  SMPS characteristic Switched Mode Power Supply  preparation: Please connect, the test cases referred resistors between the inputs: PTC_1 and PTC_6	4		quiescent current consumption: 24V_HL2 @ 24VDC current: SENSING SMPS	mA											4,00	100,00	200,00			
			SW_TEMP_SENSOR : HL2	kHz											180,00	200,00	220,00			
	3		5V_HL2 : HL2												4,75	5,00	5,25			
			PTC_ADC: HL2 @ open PTC_1/PTC_6	V											3,00	3,70	5,00			
			PTC_ADC: HL2 @ 1k, 1% resistor between PTC_1/PTC_6												1,00	1,20	1,80			
			PTC_ADC: HL2 @ SHORT-CIRCUIT PTC_1/PTC_6												0,00	0,32	0,50			
			PTC_1 : PTC_6	mA											4,00	4,60	5,60			
DC-Link-LED acquisition via a LED sensor  preparation: 5VDC supply: DCP_LED referenced to DCN_LED_6 (NE555 Timer-pin1)			Pilot LED flashing Frequency	Hz											5,00	7,00	15,00			
IGBT Gate Driver voltages  preparation: 1.) All drivers must be stimulated such that a connected IGBT would be switched on. Add an IGBT Gate-Emitter load, a 100nF±10% ceramic or metal foil capacitor must be connected between the measuring points: IGBT Gate to IGBT Emitter RUP_G11 : RUP_E11, RUN_G21 : RUN_E21 SVP_G11 : SVP_E11, SVN_G21 : SVN_E21 TWP_G11 : TWP_E11, TWN_G21 : TWN_E21  short circuit: IGBT Collector to IGBT Emitter RUP_C1 : RUP_E11 : RUN_E21 SVP_C1 : SVP_E11 : SVN_E21 TWP_C1 : TWP_E11 : TWN_E21  2.) only GAA26800MX2 OUT_EN_CONV:GND set to HIGH level			RUP_G11:RUP_E11@PWM_RP, PWM_UP=HIGH:GND	V										-16,00	-9,50	-5,00				
			RUP_G11:RUP_E11@PWM_RP, PWM_UP=LOW:GND												14,00	15,70	17,00			
			RUN_G21:RUN_E21@PWM_RN, PWM_UN=HIGH:GND												-16,00	-9,50	-5,00			
			RUN_G21:RUN_E21@PWM_RN, PWM_UN=LOW:GND												14,00	15,70	17,00			
			SVP_G11:SVP_E11@PWM_SP, PWM_VP=HIGH:GND												-16,00	-9,50	-5,00			
			SVP_G11:SVP_E11@PWM_SP, PWM_VP=LOW:GND												14,00	15,70	17,00			
			SVN_G21:SVN_E21@PWM_SN, PWM_VN=HIGH:GND												-16,00	-9,50	-5,00			
			SVN_G21:SVN_E21@PWM_SN, PWM_VN=LOW:GND												14,00	15,70	17,00			
			TWP_G11:TWP_E11@PWM_TP, PWM_WP=HIGH:GND												-16,00	-9,50	-5,00			
			TWP_G11:TWP_E11@PWM_TP, PWM_WP=LOW:GND												14,00	15,70	17,00			
			TWN_G21:TWN_E21@PWM_TN, PWM_WN=HIGH:GND												-16,00	-9,50	-5,00			
			TWN_G21:TWN_E21@PWM_TN, PWM_WN=LOW:GND												14,00	15,70	17,00			



Test Requirement for PBX_BIDI GAA26800MX										Samples										Value range  Lower Specification Limit Upper Specification Limit		
1. All measuring instruments must be calibrated!!! 2. As an additional document, the circuit diagram of the PCBA is required. 3. All measuring points : reference points are described in kind of netnames, test points or component designator. 4. PBX_BIDI alternatively assembled with CONVERTER- or INVERTER-FUNCTIONALITY test cases <b>only</b> for PBX_BIDI, <b>INVERTER</b> -FUNCTIONALITY, GAA26800MX1, marked with note: 1 test cases <b>only</b> for PBX_BIDI, <b>CONVERTER</b> -FUNCTIONALITY, GAA26800MX2, marked with note: 2 test cases <b>not required for GAA26800MX1, GAA26800MX2</b> , marked with note: 4 5. Highly Accelerated Life Test, test cases required for <b>HALT</b> , marked with note: 3																						
Test cases										Board Serial Number										LSL	Typical	USL
Description	note	note	measuring point : reference point @ specified condition				unit															
<b>DRIVER_RESET_N logic low pulse width</b>  <b>Description of the function:</b> HCPL316J FAULT* changes from a high impedance state to a logic low, if the voltage on the HCPL316J <b>DESAT</b> pin exceeding an internal reference voltage of 7.5V <b>while the IGBT is on</b> . HCPL316J FAULT* output remains low until HCPL316J RESET* is brought low. HCPL316J FAULT* output is an open collector which allows the FAULT* outputs from all HCPL-316Js to be connected together in a "wired OR" forming the signals: GAA26800MX1: <b>OCT_INV</b> referenced to GND GAA26800MX2: <b>CNV_OC_FLT</b> referenced to GND  When one of the six HCPL316J <b>FAULT*</b> outputs change to low, the HCPL316J <b>RESET*</b> input will <b>change to low after a time delay</b> of the "DRIVER_RESET_N logic low pulse width"  <b>preparation:</b> 1.) All drivers must be stimulated such that a connected IGBT would be <b>switched on</b> . PWM_RP= <b>LOW</b> :GND, PWM_UP= <b>LOW</b> :GND PWM_RN= <b>LOW</b> :GND, PWM_UN= <b>LOW</b> :GND PWM_SP= <b>LOW</b> :GND, PWM_VP= <b>LOW</b> :GND PWM_SN= <b>LOW</b> :GND, PWM_VN= <b>LOW</b> :GND PWM_TP= <b>LOW</b> :GND, PWM_WP= <b>LOW</b> :GND PWM_TN= <b>LOW</b> :GND, PWM_WN= <b>LOW</b> :GND  2.) Add an IGBT Gate-Emitter load, a 100nF±10% ceramic or metal foil capacitor must be connected between the measure points: IGBT Gate to IGBT Emitter RUP_G11 : RUP_E11, RUN_G21 : RUN_E21 SVP_G11 : SVP_E11, SVN_G21 : SVN_E21 TWP_G11 : TWP_E11, TWN_G21 : TWN_E21  3.) <b>Realize the following possibility to change between:</b> short circuit / <b>open for approximate 1ms</b> : IGBT Collector to IGBT Emitter RUP_C1 : RUP_E11, RUP_E11 : RUN_E21 SVP_C1 : SVP_E11, SVP_E11 : SVN_E21 TWP_C1 : TWP_E11, TWP_E11 : TWN_E21  4.) only GAA26800MX2 OUT_EN_CONV:GND set to HIGH level  <b>stimulation:</b> <b>DESAT pins are executed successively by open only one of the short circuit "IGBT Collector to IGBT Emitter" for approximate 60ms.</b> Keep a wait time condition to the next test case of approximate 500ms. All tests must be processed 2 times sequentially, in order to guarantee that no latch up effect appears.																						
	GAA26800MX1: <b>OCT_INV</b> referenced to GND GAA26800MX2: <b>CNV_OC_FLT</b> referenced to GND  <b>HIGH pulse width</b> @open <u>only</u> short circuit RUP_C1 : RUP_E11															200	360	500				
	GAA26800MX1: <b>OCT_INV</b> referenced to GND GAA26800MX2: <b>CNV_OC_FLT</b> referenced to GND  <b>HIGH pulse width</b> @open <u>only</u> short circuit RUP_E11 : RUN_E21															200	360	500				
	GAA26800MX1: <b>OCT_INV</b> referenced to GND GAA26800MX2: <b>CNV_OC_FLT</b> referenced to GND  <b>HIGH pulse width</b> @open <u>only</u> short circuit SVP_C1 : SVP_E11															200	360	500				
	GAA26800MX1: <b>OCT_INV</b> referenced to GND GAA26800MX2: <b>CNV_OC_FLT</b> referenced to GND  <b>HIGH pulse width</b> @open <u>only</u> short circuit SVP_E11 : SVN_E21				ms											200	360	500				
	GAA26800MX1: <b>OCT_INV</b> referenced to GND GAA26800MX2: <b>CNV_OC_FLT</b> referenced to GND  <b>HIGH pulse width</b> @open <u>only</u> short circuit TWP_C1 : TWP_E11															200	360	500				
	GAA26800MX1: <b>OCT_INV</b> referenced to GND GAA26800MX2: <b>CNV_OC_FLT</b> referenced to GND  <b>HIGH pulse width</b> @open <u>only</u> short circuit TWP_E11 : TWN_E21															200	360	500				

Test Requirement for PBX_BIDI GAA26800MX																				
1. All measuring instruments must be calibrated!!! 2. As an additional document, the circuit diagram of the PCBA is required. 3. All measuring points : reference points are described in kind of netnames, test points or component designator. 4. PBX_BIDI alternatively assembled with CONVERTER- or INVERTER-FUNCTIONALITY test cases <b>only</b> for PBX_BIDI, <b>INVERTER</b> -FUNCTIONALITY, GAA26800MX1, marked with note: 1 test cases <b>only</b> for PBX_BIDI, <b>CONVERTER</b> -FUNCTIONALITY, GAA26800MX2, marked with note: 2 test cases <b>not required for GAA26800MX1, GAA26800MX2</b> , marked with note: 4 5. Highly Accelerated Life Test, test cases required for <b>HALT</b> , marked with note: 3										Samples								Value range  Lower Specification Limit Upper Specification Limit		
Test cases										Board Serial Number								LSL	Typical	USL
Description	note	note	measuring point : reference point @ specified condition	unit																
POWER FAIL MONITORING thresholds PFAIL_RS_CONV signal changes from 1.) statical LOW level 2.) TOGGLE between LOW and HIGH 3.) statical HIGH level  Umax_line_to_line=480V*1.1 resultant max. voltage range: ±3.7V (Vpp=7.4V) Umin_line_to_line=340V resultant min. voltage: Vpp=4.76V  preparation: adjustable sinus voltage supply 7.4Vpp@50Hz, offset=0V to US / GND_SENSE	2		PFAIL_RS_CONV / GND threshold toggle Decrease US from 7.4Vpp until PFAIL_RS_CONV threshold changes from statical LOW to TOGGLE	Vpp											1,00	1,30	4,76			
			PFAIL_RS_CONV / GND threshold statical LOW Decrease US from 7.4Vpp until PFAIL_RS_CONV threshold changes from TOGGLE to statical HIGH												0,30	0,70	1,00			
Hall Effect Current Sensor LEM: LA200-P TAMURA: S26P200D15Y VAC: T60404-N4646-X201 current conversion ratio: 1:2000 measure the output-current at a given input-current  preparation: Apply R=60ohm between: SENSE_IR, SENSE_IU and GNDA SENSE_IS, SENSE_IV and GNDA  Input-current source cable put through the hole once. Polarity markings: A positive measuring output-current is obtained on terminal M (pin 2), when the primary input-current flows in the direction of the arrow.			SENSE_IR, SENSE_IU : GNDA output-current @ 0A	mA											-1,00	0,00	1,00			
			SENSE_IR, SENSE_IU : GNDA LEM_IR_output-current @ 2A											0,80	1,00	1,20				
			SENSE_IR, SENSE_IU : GNDA LEM_IR_output-current @ -2A											-1,20	-1,00	-0,80				
			SENSE_IS, SENSE_IV : GNDA LEM_IS_output-current @ 0A											-1,00	0,00	1,00				
			SENSE_IS, SENSE_IV : GNDA LEM_IS_output-current @ 2A											0,80	1,00	1,20				
			SENSE_IS, SENSE_IV : GNDA LEM_IS_output-current @ -2A											-1,20	-1,00	-0,80				
CHG-RELAY contact resistance  preparation: OUT_EN_INV:GND set to HIGH level OUT_EN_CONV:GND set to HIGH level  REL1, REL2: contacts closed CHRG_N:GND to LOW  REL1, REL2: contacts opened CHRG_N:GND to HIGH	2		R_RES:RUO@REL1, REL2: contacts opened	YES or NO											contacts opened					
			R_RES:RUO@REL1, REL2: contacts closed											contacts closed						
			S_RES:SVO@REL1, REL2: contacts opened											contacts opened						
			S_RES:SVO@REL1, REL2: contacts closed											contacts closed						

Test Requirement for PBX_BIDI GAA26800MX					Samples										Value range  Lower Specification Limit Upper Specification Limit				
1. All measuring instruments must be calibrated!!! 2. As an additional document, the circuit diagram of the PCBA is required. 3. All measuring points : reference points are described in kind of netnames, test points or component designator. 4. PBX_BIDI alternatively assembled with CONVERTER- or INVERTER-FUNCTIONALITY test cases <b>only</b> for PBX_BIDI, <b>INVERTER</b> -FUNCTIONALITY,   GAA26800MX1, marked with note: 1 test cases <b>only</b> for PBX_BIDI, <b>CONVERTER</b> -FUNCTIONALITY, GAA26800MX2, marked with note: 2 test cases <b>not required</b> for GAA26800MX1, GAA26800MX2, marked with note: 4 5. Highly Accelerated Life Test, test cases required for <b>HALT</b> , marked with note: 3																			
Description		Test cases		unit	Board Serial Number										LSL	Typical	USL		
	note	note	measuring point : reference point @ specified condition																
VRS, VST voltage gain calibration and transfer gain K3 (plausibility) check  Linear Optocoupler GAA629CL1 Vendor Vishay: IL300-EF-X017T transfer gain K3 = 0.851 - 1.061 ± 0.5% Tamb = 0 °C to 75 °C  Vendor Agilent / Avago: HCNR201 transfer gain K3 = 0.93 - 1.07	2		REF_SEC / GNDA (±10%) equation: $5V \cdot -0.4115 \cdot 0.89111 = -1.83356V$	mV											-2017,40	-1834,00	-1650,60		
			measuring point: DC_VRS / SGND (±10%) signal: VRS_DC_N / GND_SENSE												1852,20	2058,00	2263,80		
			measuring point: VRS / AGND (±25%) signal: VRS_OUT_DC_N / GNDA equation: $2.0576V \cdot 0.89111 = 1.8335V$												1375,50	1834,00	2292,50		
				measuring point: VRS_N / AGND signal: VRS_OUT_N / GNDA												-1500,00	0,00	1500,00	
				transfer gain K3_VRS (plausibility) check proceeding: calculate with the following equation: $K3\_VRS = VRS\_OUT\_DC\_N / (0.89111 \cdot VRS\_DC\_N)$												0,80	1,00	1,10	
				measuring point: DC_VST / SGND (±10%) signal: VST_DC_N / GND_SENSE	mV												1852,20	2058,00	2263,80
				measuring point: VST / AGND (+-25%) signal: VST_OUT_DC_N / GNDA equation: $2.0576V \cdot 0.89111 = 1.8335V$												1375,50	1834,00	2292,50	
				measuring point: VST_N / AGND signal: VST_OUT_N / GNDA													-1500,00	0,00	1500,00
					transfer gain K3_VST (plausibility) check proceeding: calculate with the following equation: $K3\_VST = VST\_OUT\_DC\_N / (0.89111 \cdot VST\_DC\_N)$												0,80	1,00	1,10
IGBT TEMPERATURE MEASUREMENT and transfer gain K3 (plausibility) check  preparation: measure with connected resistor 5kohm, ±0.1% between NTC1 / NTC2			NTC1:NTC2 (1.86V±10%) measuring point: TEMP_IGBT / GNDA signal: TEMP_IGBT / GNDA equation: typical: $(3.107V \cdot 0.89111) - 0.7258 = 2.04V$ with gain range IL300: 0.8..1.2 min.: $(0.8 \cdot 2.77V) - 0.7258 = 1.49V$ (-3% = 1.445V) max.: $(1.2 \cdot 2.77V) - 0.7258 = 2.6V$ (+3% = 2.68V)	mV											1670,00 1445,00	1860,00 2040,00	2050,00 2680,00		
			InvTempUn (Addr.: 0x12) CnvTempUn (Addr.: 0x12) measuring point: TEMP_UN / GNDA signal: TEMP_UN / GNDA												1080,00	1200,00	1320,00		
			InvTempUin (Addr.: 0x14) CnvTempUin (Addr.: 0x14) preparation: measure with connected resistor 5kohm between NTC1 / NTC2 measuring point: NTC1 / SGND signal: NTC1 / GND_SENSE												2950,00	3110,00	3270,00		
				transfer gain K3_TEMP (plausibility) check proceeding: calculate with the following equation: $K3\_TEMP = (TEMP\_IGBT + (TEMP\_UN \cdot 0.604)) / (NTC1 \cdot 0.89111)$												0,80	1,00	1,10	
DC-LINK VOLTAGE MEASUREMENT and transfer gain K3 (plausibility) check  preparation:  1.) CALIBRATED precision DC voltage reference OUTPUT VOLTAGE: +1.2V ±0.2% max LOW NOISE: 10µVPP max (0.1Hz to 10Hz) conecetld to DCP_U_ME_1 / GND_SENSE  2.) short circuit is needed between DCN_U_ME_1 / GND_SENSE	1		InvUdcIUin (Addr.: 0x18) measuring point: DC_ME / GND_SENSE signal: DC_ME / GND_SENSE equation: typical: $1.2V \cdot 2.4864 = 3V$	mV											2900,00	3000,00	3100,00		
			InvUdcIUout (Addr.: 0x1A) measuring point: UDCL / GNDA signal: UDCL / GNDA equation: typical: $3V \cdot 0.89111 = 2,673V$ with gain range IL300: 0.8..1.2 min.: $0.8 \cdot 2,673V = 2.138V$ (-3% = 2.07V) max.: $1.2 \cdot 2.673V = 3.208V$ (+3% = 3.22V)											2070,00	2673,00	3220,00			
			transfer gain K3_UDC (plausibility) check proceeding: calculate with the following equation: $K3\_UDC = UDCL / (0.89111 \cdot DC\_ME)$													0,80	1,00	1,10	

Test Requirement for PBX_BIDI GAA26800MX										Samples										Value range  Lower Specification Limit Upper Specification Limit		
1. All measuring instruments must be calibrated!!! 2. As an additional document, the circuit diagram of the PCBA is required. 3. All measuring points : reference points are described in kind of netnames, test points or component designator. 4. PBX_BIDI alternatively assembled with CONVERTER- or INVERTER-FUNCTIONALITY test cases <b>only</b> for PBX_BIDI, <b>INVERTER-FUNCTIONALITY</b> , GAA26800MX1, marked with note: 1 test cases <b>only</b> for PBX_BIDI, <b>CONVERTER-FUNCTIONALITY</b> , GAA26800MX2, marked with note: 2 test cases <b>not required for GAA26800MX1, GAA26800MX2</b> marked with note: 4 5. Highly Accelerated Life Test, test cases required for <b>HALT</b> , marked with note: 3																						
Test cases										Board Serial Number										LSL	Typical	USL
Description		note	note	measuring point : reference point @ specified condition				unit														
<div>Hardware-dependent trimming values</div> <div>assumed measured values, see table above, calculated on values in [mV] to be storing in the EEPROM low bytes from trimming values must be written into the lower addresses. GAA26800MX1: I2C DEVICE Addr.: # 2 GAA26800MX2: I2C DEVICE Addr.: # 4 I2C bus lines: GAA26800MX1: I2C_SCL0_INV, I2C_DA0_INV GAA26800MX2: I2C_SCL0_CONV, I2C_DA0_CONV</div> <div>also to be storing, informations from the board assigned label:</div> <div></div> <div></div> <div>GAA26800MX1: <b>Package code:</b> 0x00 = 20 (dez)</div> <div>GAA26800MX1: <b>voltage_code:</b> 0x02 = 4 (dez)</div> <div>GAA26800MX1: <b>power code:</b> 0x04 = 120 (dez)</div> <div>GAA26800MX1: <b>Drive version number:</b> 0x06 = 2 (dez)</div> <div>PCB serial number S/N: 0x0100..0x010F 16-byte; ASCII string; left-aligned; last bytes filled with spaces barcode; Otis definition; e.g. GAA26800MX1: "MX1093400021" GAA26800MX2: "MX2093400014"</div> <div>PCB part number P/N: 0x0120 bis 0x012F 16-byte; ASCII string; left-aligned; last bytes filled with spaces barcode; Otis definition; e.g. GAA26800MX1: "GAA26800MX1A-LF" GAA26800MX2: "GAA26800MX2A-LF"</div> <div>preparation: OUT_EN_INV:GND set to HIGH level OUT_EN_CONV:GND set to HIGH level</div>				InvTempUref (Addr.: 0x10) CnvTempUref (Addr.: 0x10) values margin: 14000..15000..16000				mV														
				InvTempUn (Addr.: 0x12) CnvTempUn (Addr.: 0x12) values margin: 1000..1202..1500																		
				InvTempUin (Addr.: 0x14) CnvTempUin (Addr.: 0x14) values margin: 1613..3107..3596																		
				InvTempUout (Addr.: 0x16) CnvTempUout (Addr.: 0x16) values margin: 1100..2769..3784 proceeding: calculate with the following equation: InvTempUout= TEMP_IGBT+9060/15000*InvTempUn CnvTempUout= TEMP_IGBT+9060/15000*CnvTempUn																		
			1	InvUdclUin (Addr.: 0x18) values margin: 2743..3000..3242																		
			2	CnvVrsUinDC (Addr.: 0x18) values margin: 4500..5000..5500 proceeding: calculate with the following equation: CnvVrsUinDC=VRS_DC_N*2.43																		
			1	InvUdclUout (Addr.: 0x1A) values margin: 1870..2667..3412																		
			2	CnvVrsUoutDC (Addr.: 0x1A) values margin: 3500..4455..5400 proceeding: calculate with the following equation: CnvVrsUoutDC=VRS_OUT_DC_N*2.43																		
			2	CnvVrsUout (Addr.: 0x1C) values margin: -1500..0..1500 constraint: if (VRS_OUT_N < 0) write (65536 - abs(VRS_OUT_N)) and if (VRS_OUT_N >= 0) then write CnvVrsUout equal to VRS_OUT_N with mV unit.																		
			2	CnvVstUinDC (Addr.: 0x1E) values margin: 4500..5000..5500 proceeding: calculate with the following equation: CnvVstUinDC=VST_DC_N*2.43																		
			2	CnvVstUoutDC (Addr: 0x20) values margin: 3500..4455..5400 proceeding: calculate with the following equation: CnvVstUoutDC=VST_OUT_DC_N*2.43																		
			2	CnvVstUout (Addr: 0x22) values margin: -1500..0..1500 constraint: if (VST_OUT_N < 0) write (65536 - abs(VST_OUT_N)) and if (VST_OUT_N >= 0) then write CnvVstUout equal to VST_OUT_N with mV unit.																		
			1	InvManufTestId (addr: 0x1C) must be set to enable the trimming parameter with set 0xDEC0 after end of hardware test&calibration addr: 0x1C data: C0 addr: 0x1D data: DE					HEX													
			2	CnvManufTestId (addr: 0x24) must be set to enable the trimming parameter with set 0xDEC0 after end of hardware test&calibration addr: 0x24 data: C0 addr: 0x25 data: DE																		